

Securing Custom Computing Devices: Observations from the Lab and the Market

Prepared for SCCM 2025

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Securing Custom Computing Devices: Observations from the Lab and the Market

Dr. Jonathan Graf, CEO of Graf Research, will share how Graf Research is *developing a new generation of configurable computing tools* for electronic design automation and verification—tools that create independent, trustworthy views of FPGA configuration and silicon correctness.

Among these innovations is a method for bitstream equivalence checking, Enverité PV-Bit, which confirms whether an FPGA bitstream truly matches the intended gate-level netlist. Another is Ensofic, a silicon attestation platform that combines soft sensors with machine learning to evaluate both the reliability and authenticity of an FPGA, including the ability to spot counterfeit devices.

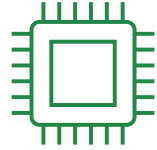
The talk will also cover what it takes to turn *research prototypes into practical, commercial-grade solutions* ready for deployment in high-stakes industries like aerospace, automotive, defense, and energy. Drawing on hands-on experience with deployed commercial solutions, Dr. Graf will outline key lessons learned and show how these projects have inspired unexpected new applications. The result is a clear picture of challenges and how the security of custom computing machines can advance rapidly in the years ahead.



Graf Research R&D Areas



Microelectronics
Trust & Assurance



FPGA Design &
Verification



Machine Learning



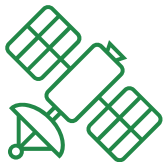
Circuit Analysis



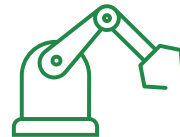
Digital Signal
Processing



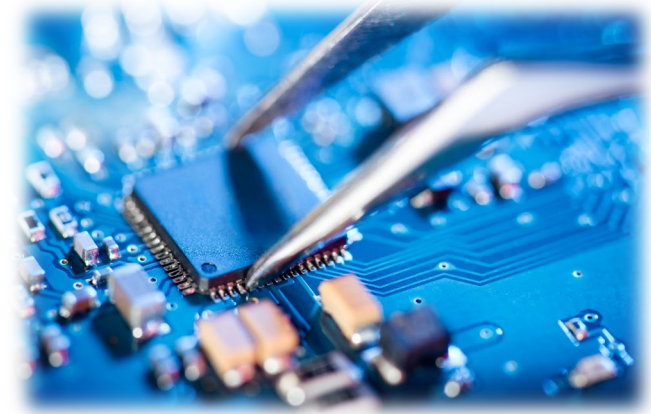
Anti-Tamper
Technologies



Software Defined
Radio



Laboratory
Automation



Enverité by Graf Research

EDA for FPGA Design Assurance



Evaluates the equivalence of an FPGA bitstream and its physical netlist



Creates and verifies a tamper-evident auditable digital thread as a design traverses the build flow



Come to the AMD Security Working Group in Colorado, D.C., or *Munich* this Fall to see this tool demonstrated!



PhD Side



CEO Side



Agenda

Two SCCM Challenges and Two Graf Research technologies from the PhD and CEO perspective

Challenge 1 : Verify Bitstream Contents

- FPGA Bitstream Equivalence Checking Software



Challenge 2 : Find Counterfeit FPGAs

- Counterfeit FPGA detection through soft sensors and machine learning



CHALLENGE 1

Verify Bitstream Contents

Previous: Verify through Reverse Engineering



Fig. 3. Luna's Change Detection Platform (CDP)

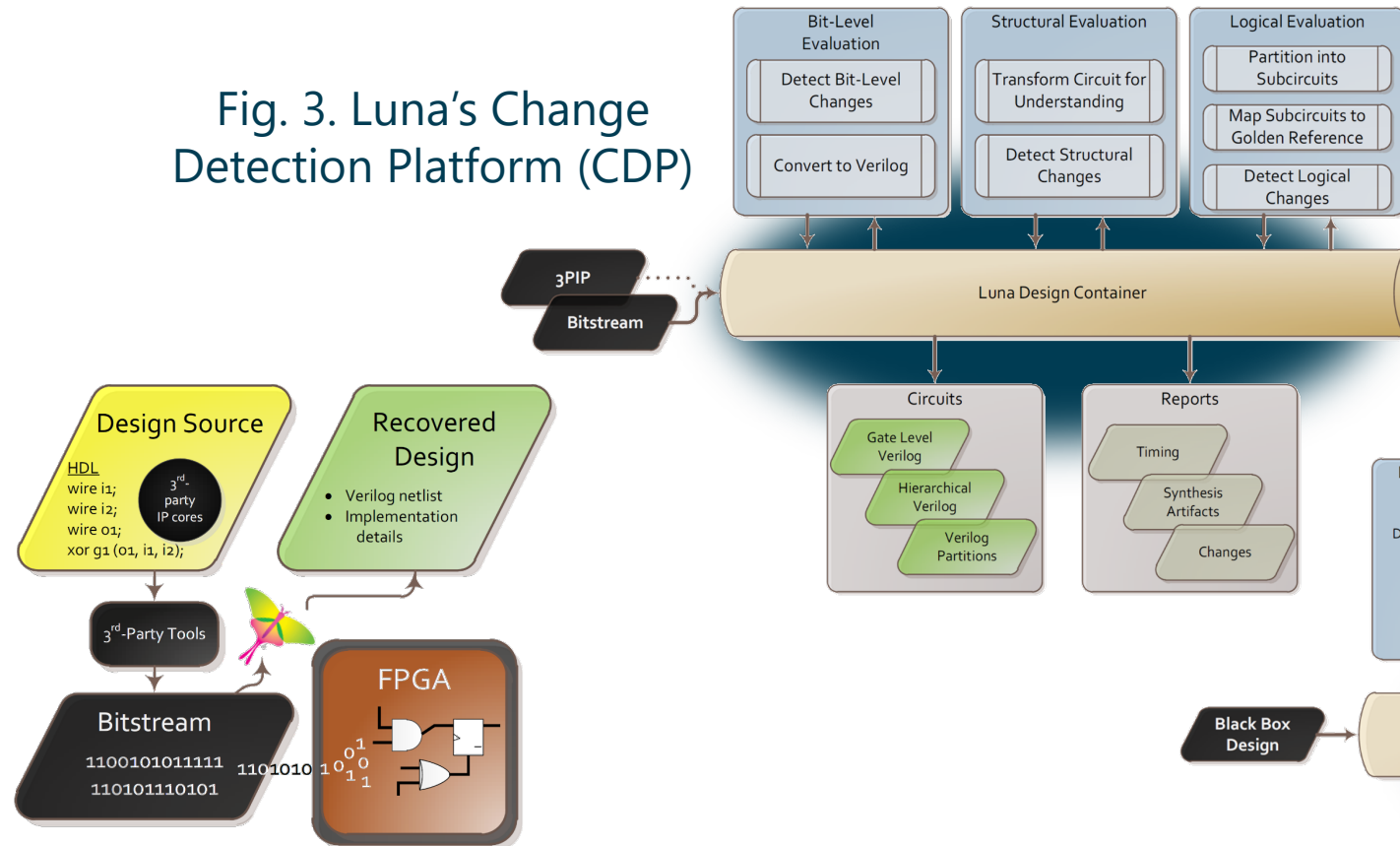
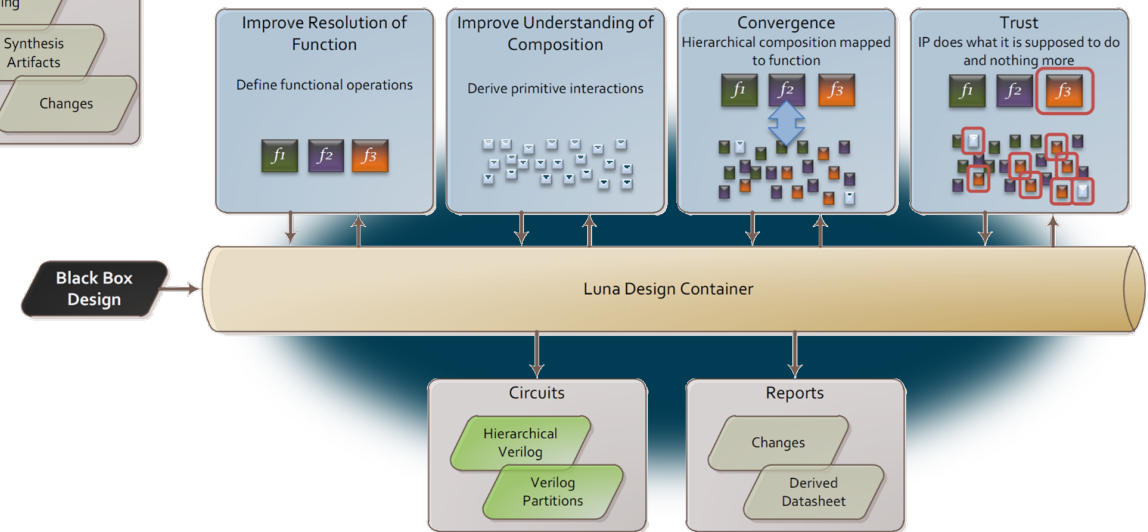


Fig. 1. Recovering design details from a bitstream

Fig. 4. Luna's Functional Derivation Platform (FDP)



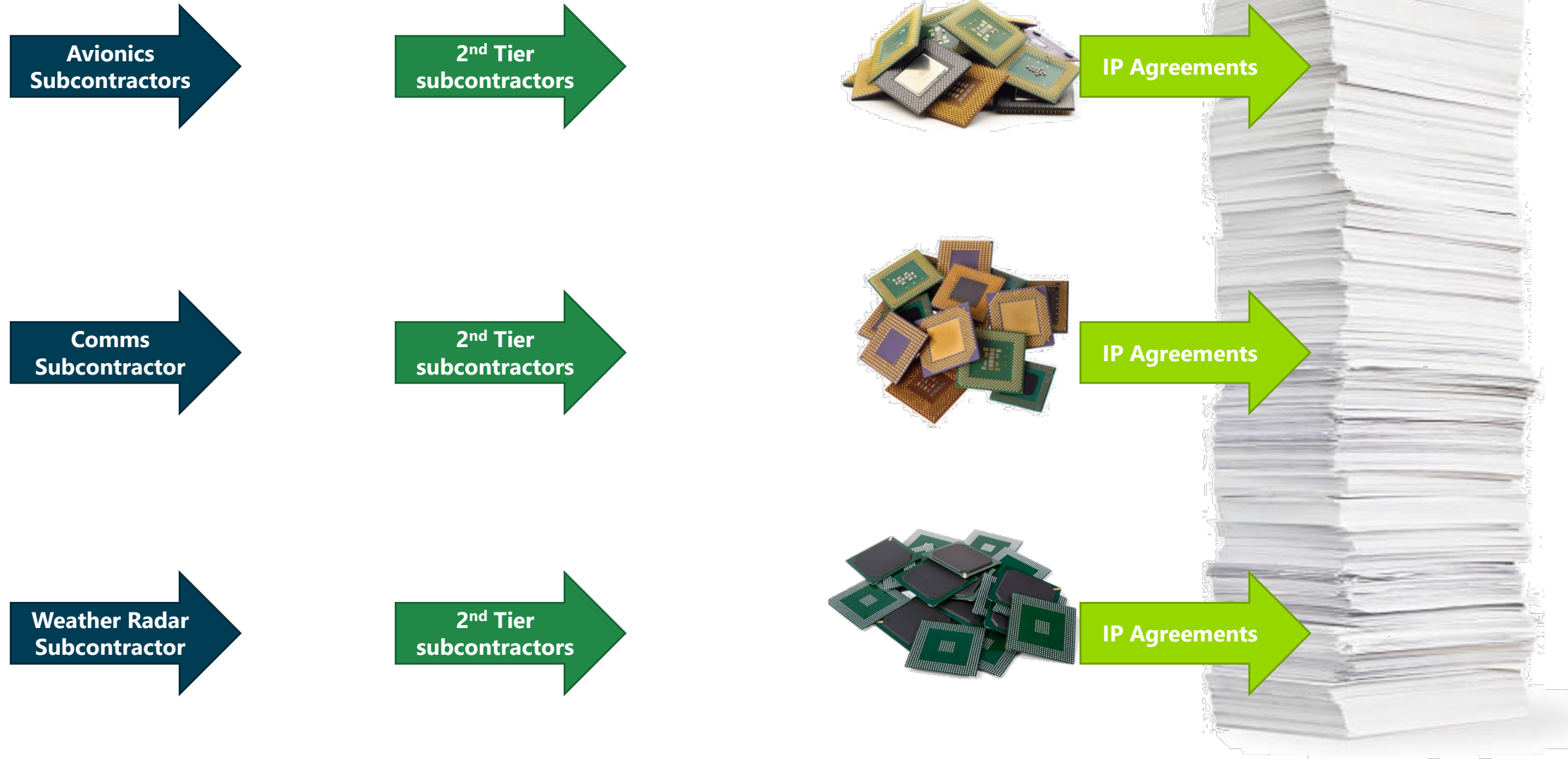
J. Graf, S. Harper, L. Lerner, "The Integrity of FPGA Designs: Capabilities Enabled by Unlocking Bitstreams and 3rd-Party IP," GOMAC 2012

J. Graf, S. Harper, L. Lerner, "Ensuring Design Integrity through Analysis of FPGA Bitstreams and IP Cores," ERSA 2012 Keynote



Verify the Bits the Fly?

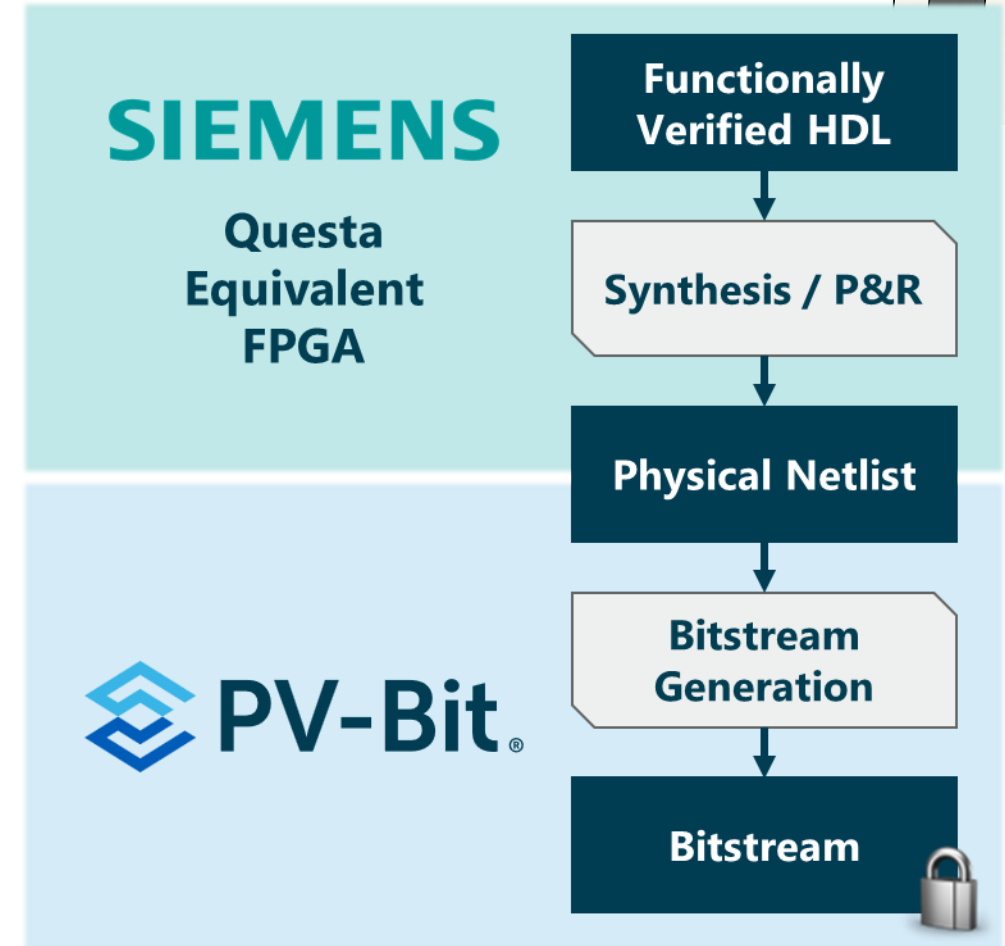
Hard Lesson Learned about RE-based Verification from an Aviation Platform



New: HDL-to-Bitstream Equivalence Checking



- Ensures **unintended errors and/or malicious modifications have NOT been inserted** during the design build flow
- Pairing **Questa Equivalent FPGA** with **Enverité PV-Bit** creates a verification toolchain that performs HDL-to-bitstream equivalence checking
 - Precondition: HDL is functionally verified
 - Questa Equivalent FPGA: Verifies the logical equivalence between the HDL and Physical Netlist
 - Enverite PV-Bit: Verifies the physical and logical equivalence between the Physical Netlist and Bitstream



New: HDL-to-Bitstream Equivalence Checking



**Automated Evaluation of Physical
and Logical Equivalence**

Designed for the Typical End User

Respects FPGA Vendor Bitstream

Respects Third Party Vendor IP

SIEMENS

**Questa
Equivalent
FPGA**

**Functionally
Verified HDL**

Synthesis / P&R

Physical Netlist

**Bitstream
Generation**

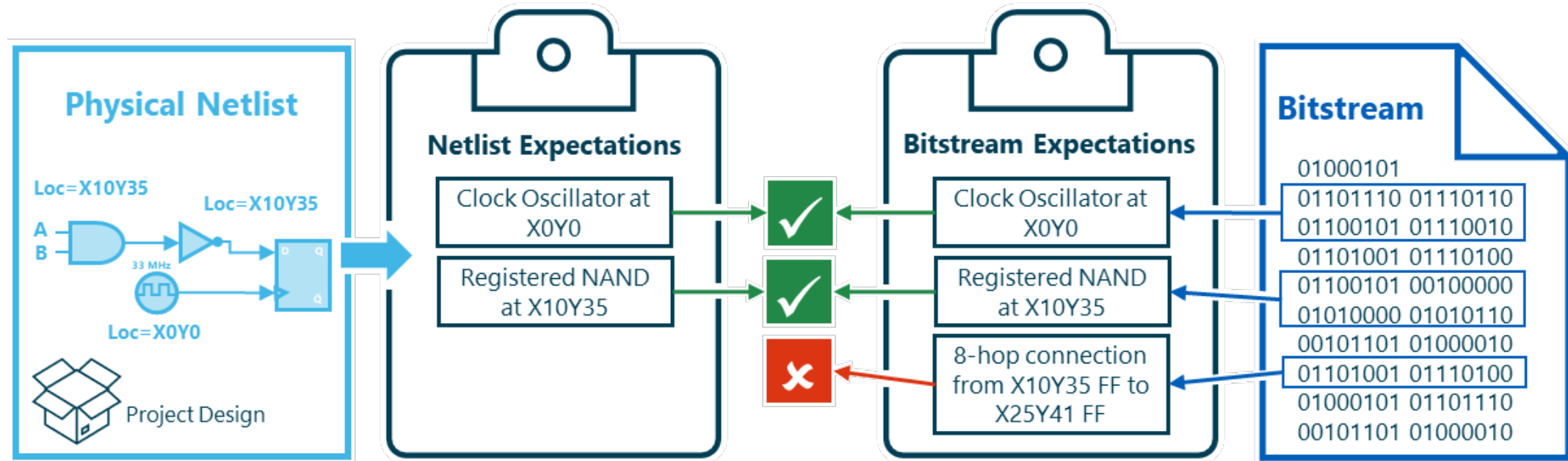
Bitstream

 **PV-Bit®**



Enverité PV-Bit Verification Process

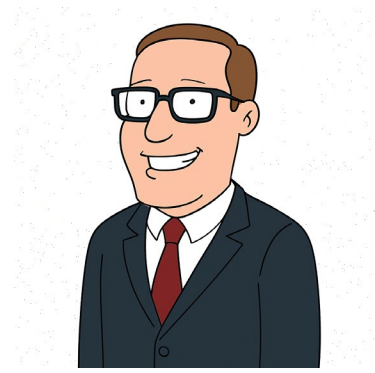
A Logical and Physical Equivalence Check in the Properties Domain



AMD, Lattice, Altera, and Microchip logos are registered trademarks of their respective corporations



Lessons Learned



Make what the SCCM market wants, not just what it needs

Make your SCCM solution work with, not against, the interest of Silicon Valley

Bootstrap – VCs are often not patient enough for SCCM solutions



CHALLENGE 2

Find Counterfeit FPGAs

Pre-existing Solutions



Image credit : Battelle



EnsofIC Tool Suite

- **EnsofIC Foundation**

- Soft sensors to extract knowledge from FPGAs
- Support for AMD Xilinx and Altera devices
- Techniques readily extendable to other vendors and device types
- Broadly applicable throughout the supply chain

- **Attest**

- Platform for detecting counterfeit FPGAs without external equipment
- Non-destructive, at-rest or at-boot

- **Inspect**

- Platform for analyzing characteristics of FPGA silicon
- Data transformations, analyses, visualizations, and reporting





EnsofIC Attest & Inspect

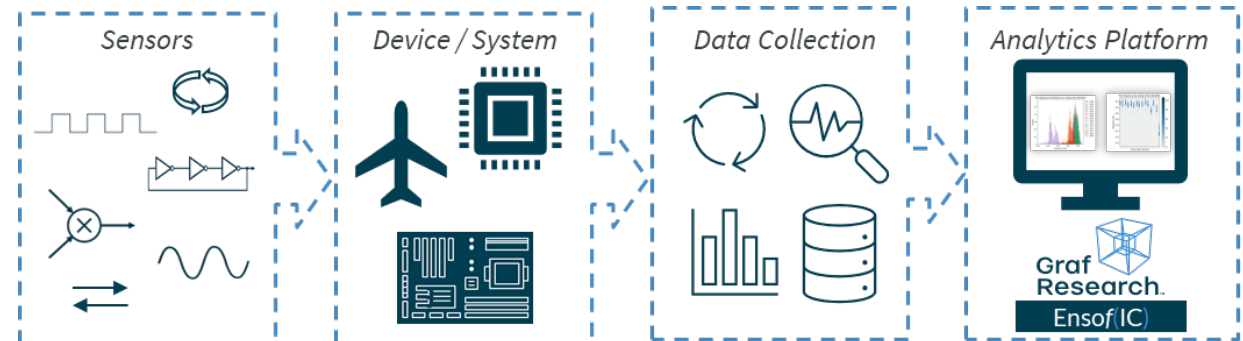
- **Attest:** For a *user of any skill* who simply wants to *quickly ascertain* whether a device is *genuine or counterfeit*

- Genuine / counterfeit classification
- Focused on repackaged counterfeits
- ID devices as quickly as possible
- Abstracts—away raw sensor data

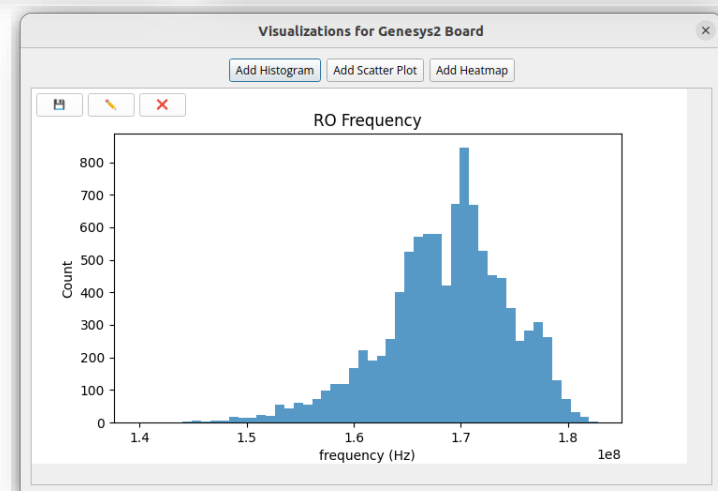
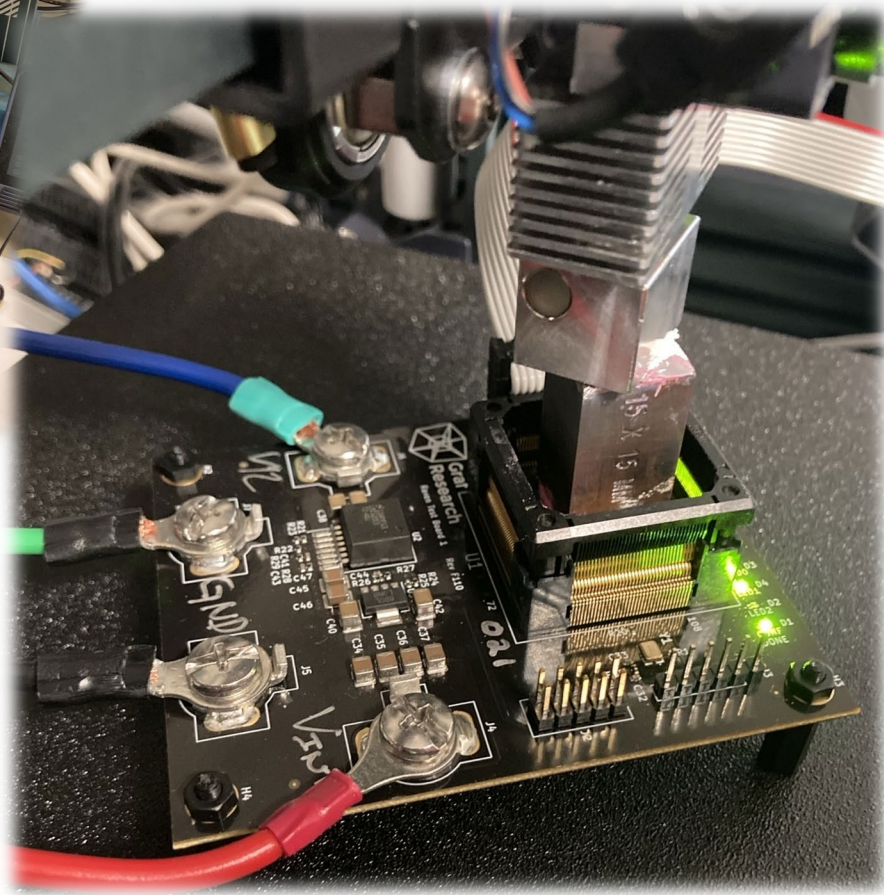
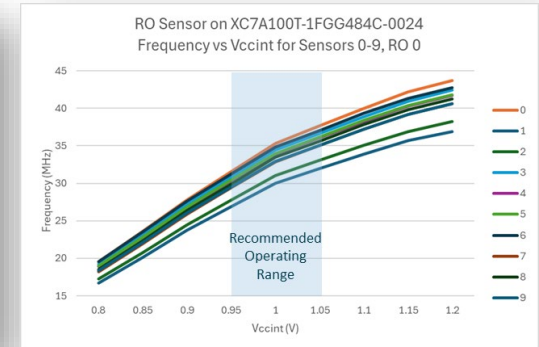
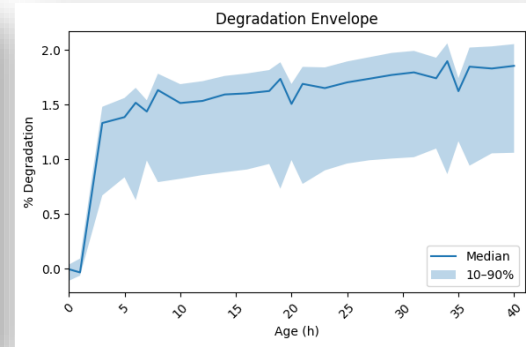
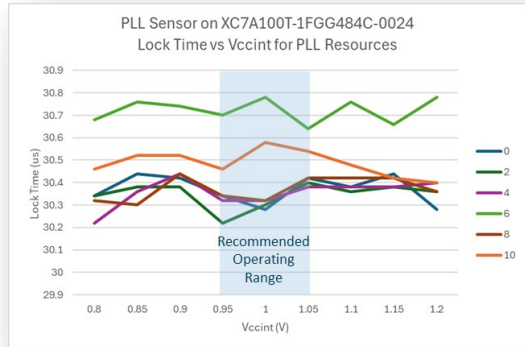
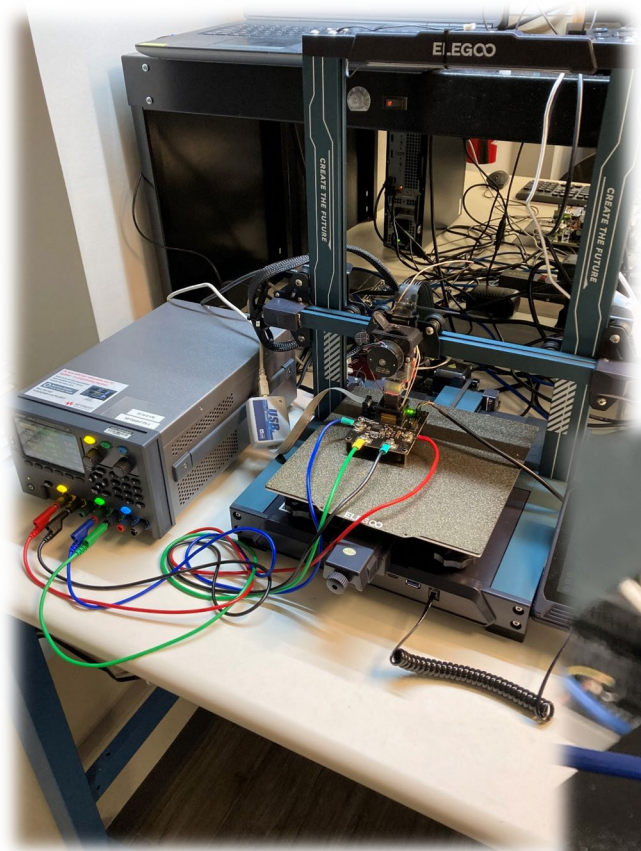


- **Inspect:** For an *analyst or engineer* who wants a powerful suite of sensors that can *interrogate the FPGA silicon*, producing *data that can be analyzed* in both currently recognized and future/extensible ways

- In-depth analytics using statistics, transformations, and visualizations
- Examine inter- and intra-device relationships
- Directly access to raw sensor data
- Extensible to new analytics and sensors



Patent Pending: Application No. 63/462,604



EnsofIC Attest - Part Classification

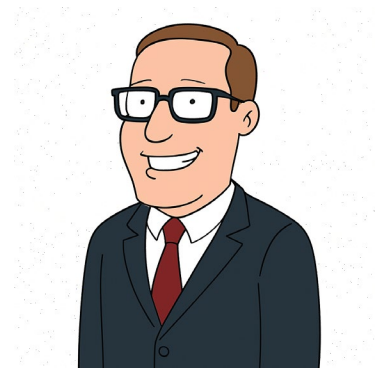
SUSPECT DEVICE - FURTHER INVESTIGATION REQUIRED
Predicted mismatch for FPGA Date Code

Xilinx Artix 7 XC7A100T-1FGG484C

	Target	Expected	Predicted	Confidence
XC7A100T-1FGG484C-S0002	date_code	2329	2341	73.09%

Save Report

Lessons Learned



Meet the customer at their need

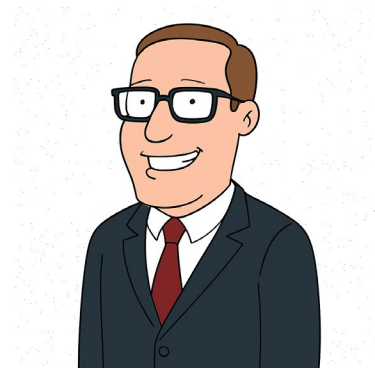
Be Apple, not Microsoft

Restate your technology in the language of the customer need



Additional Principles

Additional Lessons Learned



Incremental is not interesting

**Grow organically
(one degree principle)**

**Stick to your values
(Values — Graf Research)**

Don't make fragile solutions

Don't be a one-trick pony

Hire your SCCM classmates

**Pay attention to who is paying
for SCCM solutions**

Be fair

Have grit and hustle



For more...

At FPL 2025

- **Booth & Industrial Talk**
- **Demo of Enverité PV-Bit** finding a hardware Trojan in a bitstream (Wednesday)

PV-Bit Reading

- <https://www.grafresearch.com/pvbit>
- **J. Graf**, E. Drinkert, S. Harper, M. Winslow, A. Cook, A. A. Sohanghpurwala, T. Dunham, and W. Tabada, **"Accelerating Recertification of FPGA-Based Avionics Systems via Bitstream Equivalence Checking,"** in *Proc. 44th AIAA/IEEE Digital Avionics Systems Conf. (DASC)*, Sept. 2025.
- A. Sohanghpurwala, D. Gibson, S. Harper, **J. Graf**, and T. Dunham, **"PV-Bit: Private Verification of FPGA Bitstreams Via Bitstream Equivalence Checking,"** in *Proc. IEEE Secure Development Conf. (SecDev)*, Indianapolis, IN, USA, Oct. 2025.

EnsofIC Reading

- **W. Batchelor**, J. Koiner, C. Crofford, K. Paar, M. Winslow, M. Taylor, S. Harper, **"Attest: Non-Destructive Identification of Counterfeit FPGA Devices,"** in *Proc. IEEE Physical Assurance and Inspection of Electronics (PAINE)*, Huntsville, AL, USA, 2023.
- **W. Batchelor**, C. Crofford, M. Winslow, M. Taylor, K. Paar, J. Koiner, S. Harper, **"Towards Synthetic Data Generation for Characterization of FPGAs,"** in *GOMACTech 2025 Proc.*, Mar. 2025.
- **W. Batchelor**, C. Crofford, J. Koiner, M. Winslow, M. Taylor, K. Paar, S. Harper. **"Counterfeit FPGA Characterization and Classification with Soft Sensors and Machine Learning"** in *Proc. Ground Vehicle Systems Engineering and Technology Symp. (GVSETS)*, NDIA, Novi, MI, USA, Aug. 12–14, 2025.

